

Progress of Beamlines Design and Key Technologies of Hefei Advanced Light Facility (HALF)

Xuwei DU
xwdu@ustc.edu.cn
Beamline Team @NSRL, USTC

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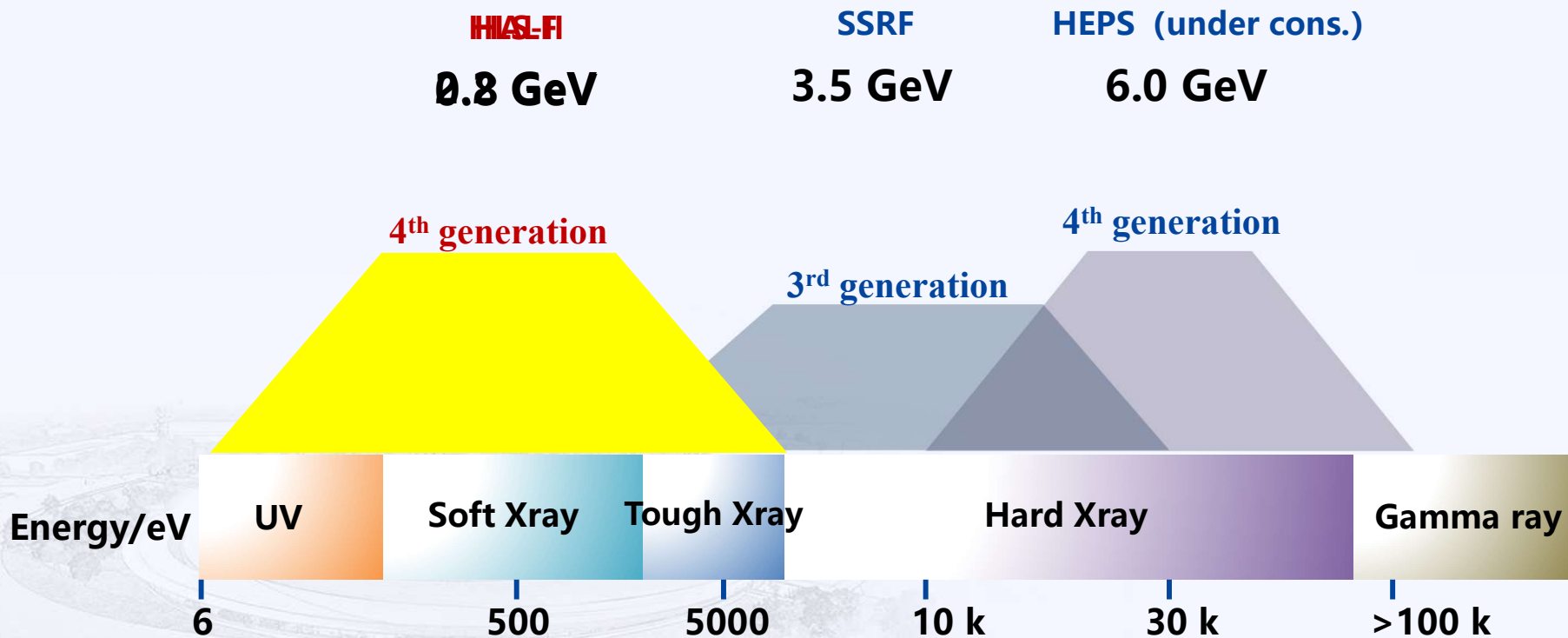


Outline

- ◆ **Introduction of HALF Project**
- ◆ **Progress of beamline design**
- ◆ **Key technologies of beamlines in HALF**

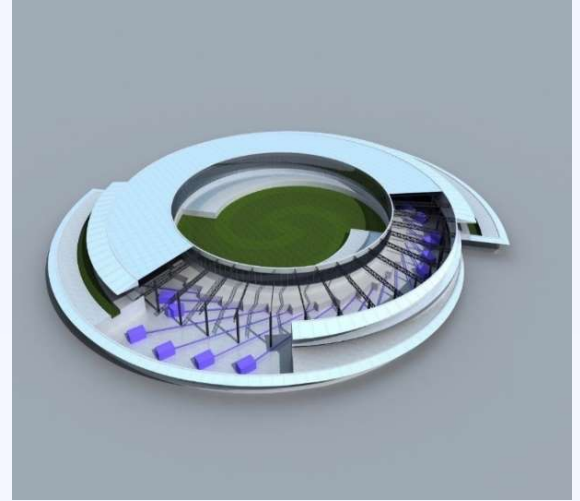


HALF: Full coverage of photon energy



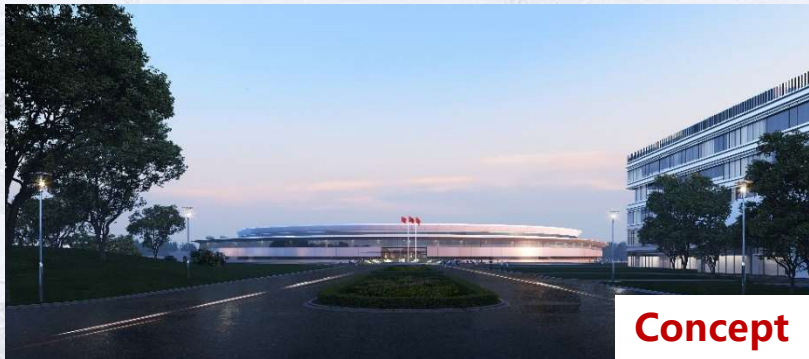
More than 3000 users expected in the phase one, more than 10000 in the future

Hefei Advanced Light Facility (HALF)



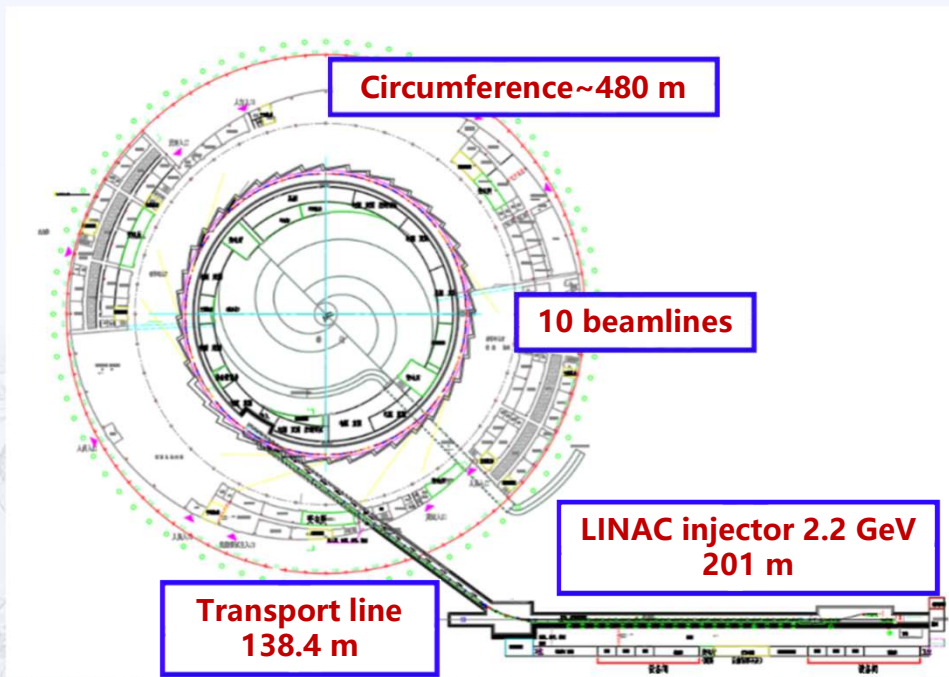
- ◆ The big eye to explore the microscopic world
- ◆ HALF: Beamline scientist + User, Instrument development + Scientific application
- ◆ Users' participation is extremely important to the construction of HALF

Hefei Advanced Light Facility (HALF)



Engineering goal of HALF Phase I

Engineering Goal- Building the advanced 4th generation diffraction limited storage ring in the low energy range.



HALF project – Phase I:

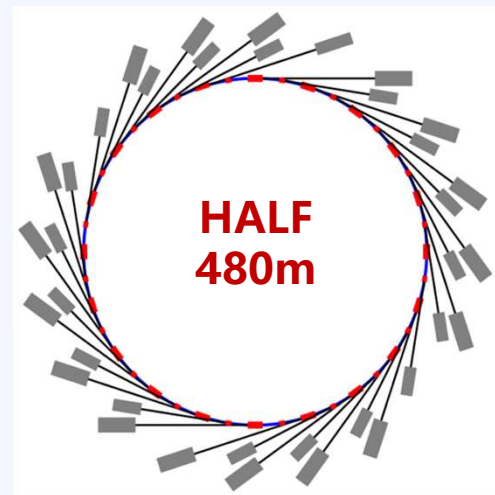
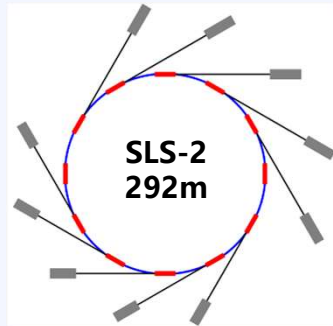
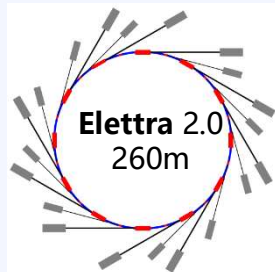
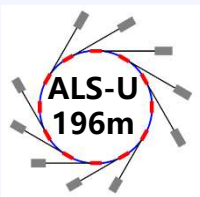
- Construction period: **64 months**, to be completed in **2028.10**,
- Total budget **2.78 billion RMB**;
- National approved in **2023.6**;
- Total of **35 beamlines** planned, **10** of them to be constructed in phase I.

Key Parameters of Storage Ring

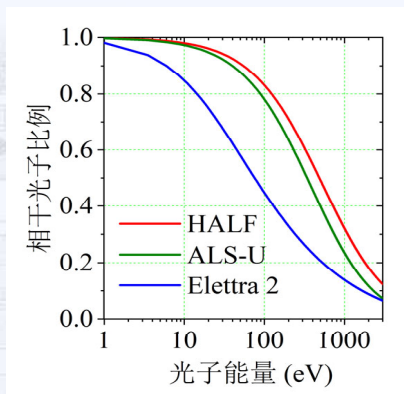
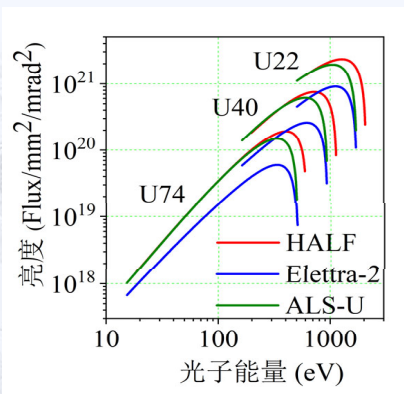
	Design	Acceptance
Energy [GeV]	2.2	2.2
Current [mA]	350	100
Circumference [m]	479.86	---
Natural emittance [pm•rad]	86.3	100
Lattice	6BA	---
Straight section number	20L+20M	---
Straight section length [m]	L/5.3, M/2.2	---
Operation mode	top-off	

- ◆ The design target should be achieved within 2 years after the acceptance test.

Advantage of HALF in low energy region



Brightest and best coherence in low energy region



- ✓ **Straight section:**
- ✓ **more quantity and longer length**
- ✓ **Brightness:**
- ✓ **2-5 orders higher compared with HLS**

Beamline overview

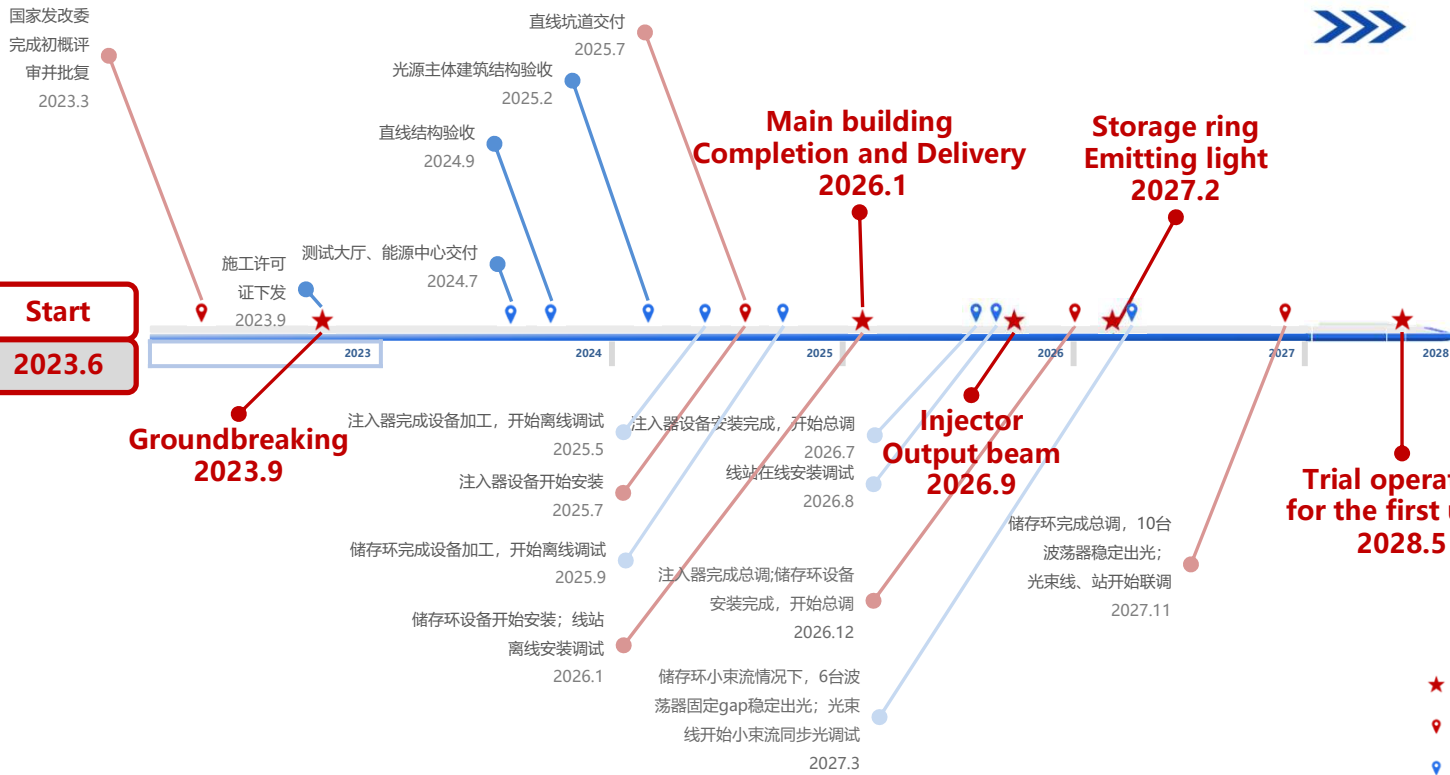
	Beamline	Energy/eV	Optical System /Monochromator	Critical parameters of Beamline
1	Mass Spectrometry for Energy Transformation and Astrochemistry	5-20	Monk-Gillieson	5,000@15eV
2	Extreme Ultraviolet Electronic Structure Characterization and Lithography	6-135	VLS-PGM	Res. P: 45,000 @21eV Spot size: 3 μm
3	Electronic Structure Characterization for Operando Micro/Nano Devices	80-1000	VLS-PGM	Res. P 22,000 @244 eV Spot size: 3 μm
4	High-sensitive, Space-Resolved and Time-Resolved Electron Spin Dynamics	250-2000	VLS-PGM	Res. P 12,000 @867eV Spot size: 3 μm
5	In-situ/Operando Soft X-ray Spectroscopy and Scattering	180-2500	VLS-PGM	Res. P: 15,000@244eV Spot size: 6 μm
6	Soft X-ray Spectromicroscopy and Ptychography	250-2500	VLS-PGM	Res. P: 15,000@400eV Coherence flux: 2.5×10^{11} phs/s@Res.p
7	Multiscale Time-Space Resolved Resonant Coherent Scattering	250-4000	VLS-PGM Multilayer Grating for 1.5-4keV	Res. P: 12,000@400eV Coherence degree 25%
8	High Throughput In-situ/Operando Tender X-ray Spectroscopy	2300-6500	DCM (2300-10000) SX700 (700-1600)	Res. P 5000@4 keV, 10000@867eV Spot size 3 μm
9	Tender X-ray Spectromicroscopy and Ptychography	2100-6500	DCM	Res. P: 15,000@4keV Coherence flux: 5×10^{10} phs/s@Res.p
10	Test Beamline	250-2000	SX700-PGM	Multifunctional design Res. P: 100,000 @867eV for HR mode

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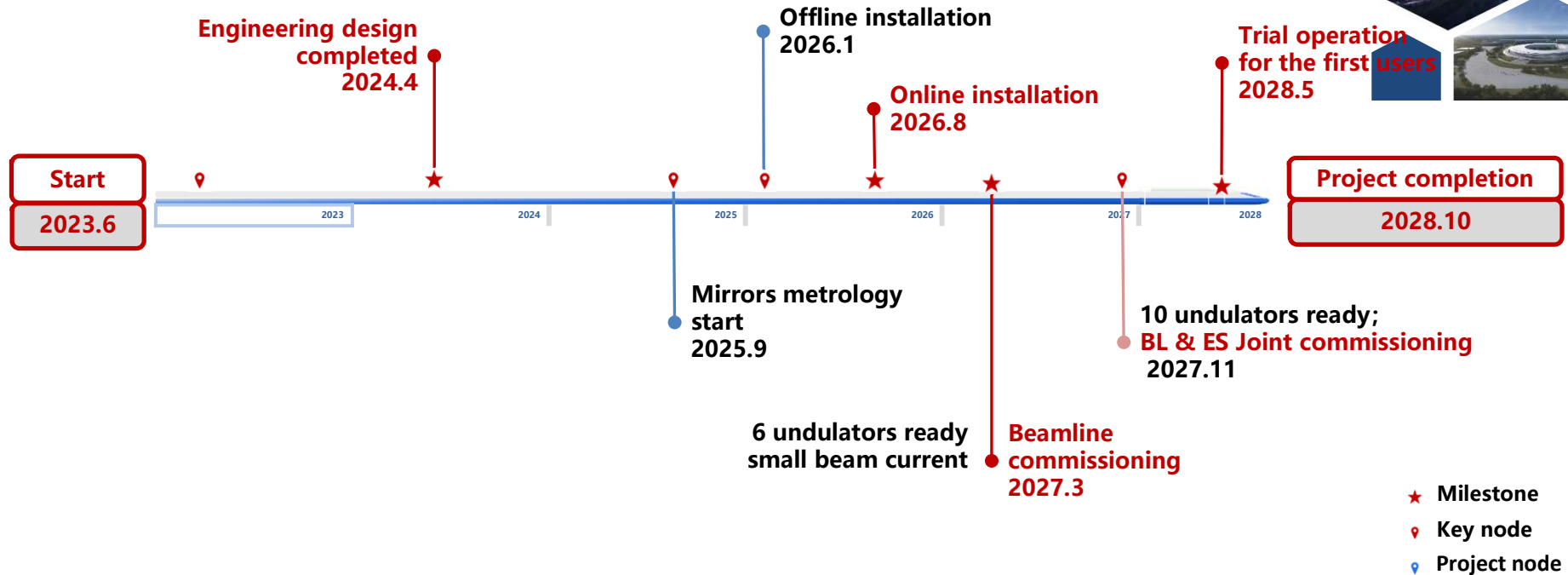


HALF Schedule



- ★ Milestone
- 📍 Key node
- 📍 Project node

Beamline Schedule



Total period of 64 months

Currently in the stage of **engineering design**

Soft X-ray Spectromicroscopy and Ptychography (soft X-ray)

Electronic Structure for Operando Micro/Nano Devices (soft X-ray)

Mass Spectrometry for Energy Transformation (VUV)

In-situ/Operando Tender X-ray Spectroscopy (tender X-ray)

Resonant Coherent Scattering (soft/tender X-ray)

Electronic State Characterization and Lithography (VUV)

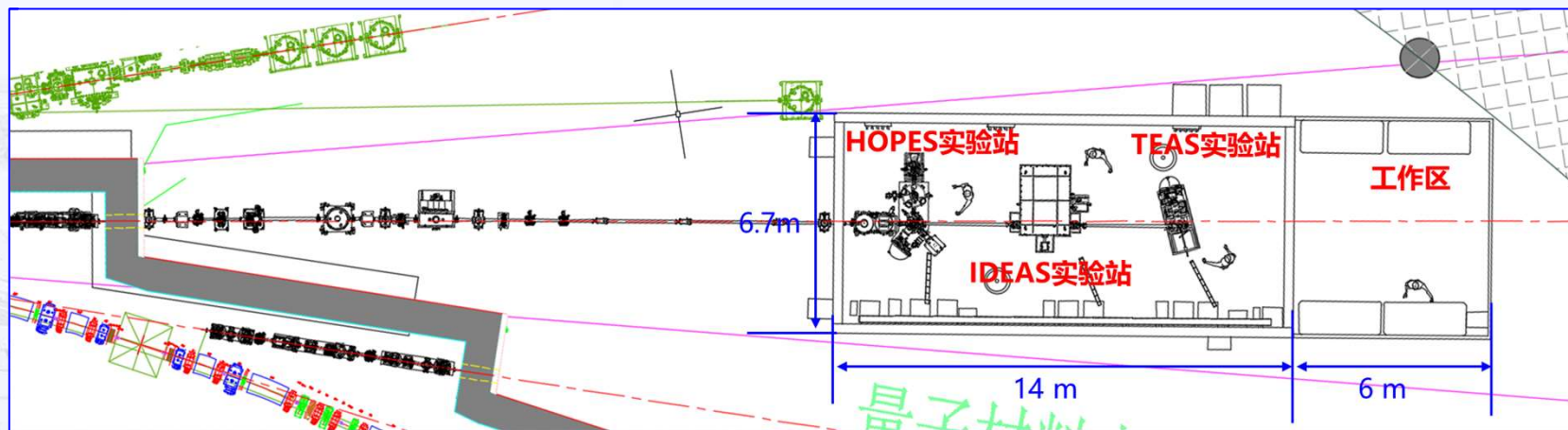
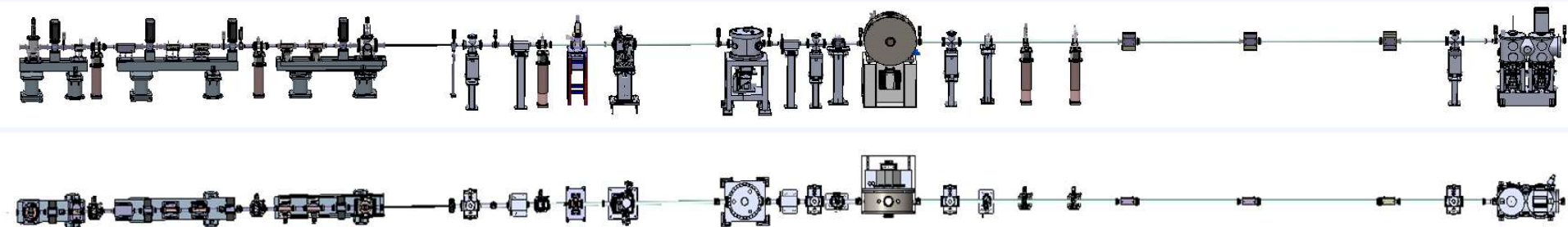
In-situ/Operando Soft X-ray Spectroscopy (soft X-ray)

Tender X-ray Spectromicroscopy and Ptychography (tender X-ray)

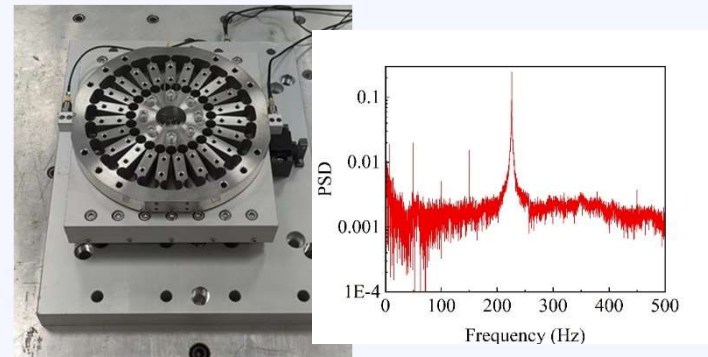
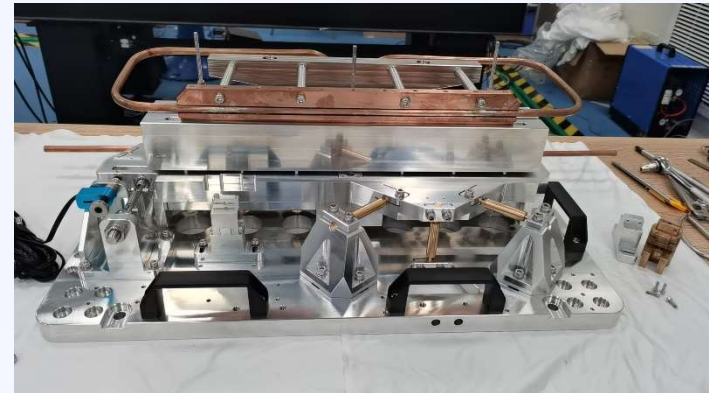
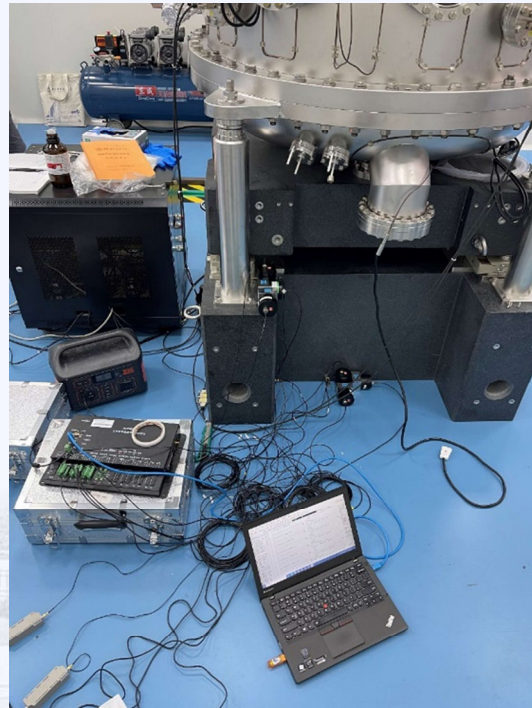
High-sensitive, Space/Time-resolved Electron Spins (soft X-ray)

Test Beamline (soft X-ray)

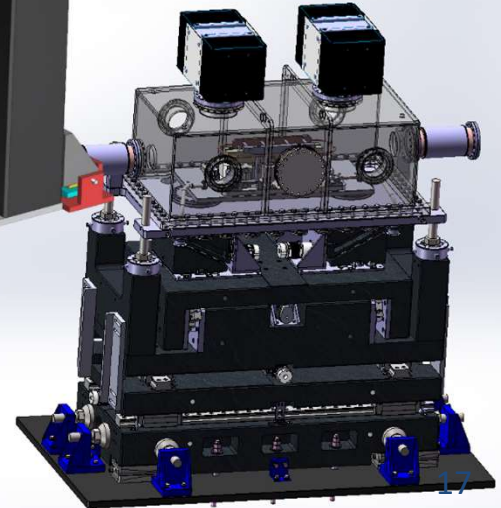
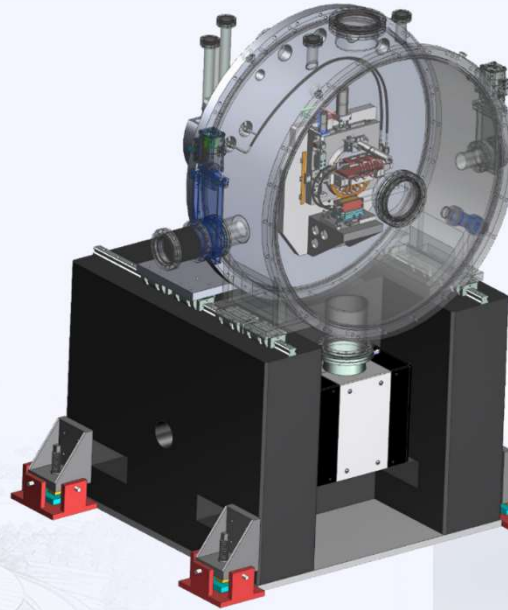
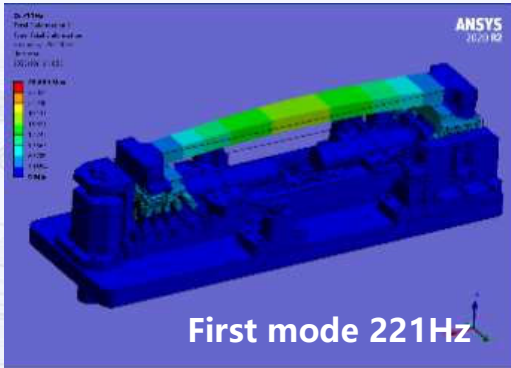
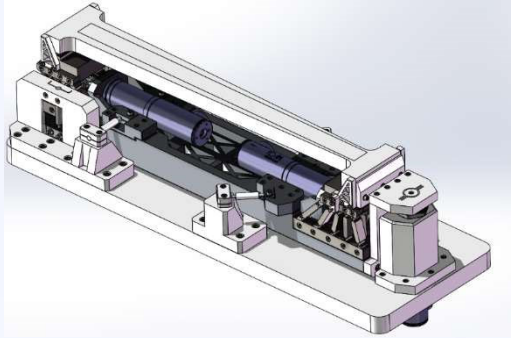
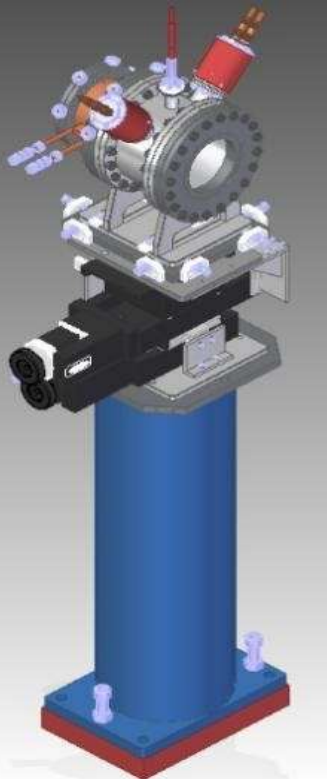
Overall layout of a beamline



Test of completed prototype



Key components design and analysis



Outline

◆ Introduction of HALF Project

◆ Progress of beamline design

◆ Key technologies of beamlines in HALF

➤ Optics:

➤ Coherence, Metrology

➤ Mechanism:

➤ High resolution of energy and space, High stability, Minimum stress clamping

➤ Cooling:

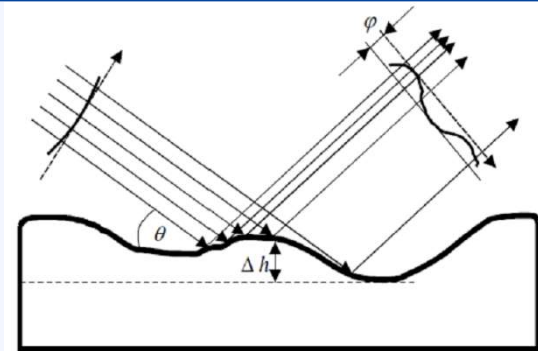
➤ High density thermal power on mirrors with ~ 100 nrad slope error and ~ 50 nrad stability

Optics: Dealing with coherent light

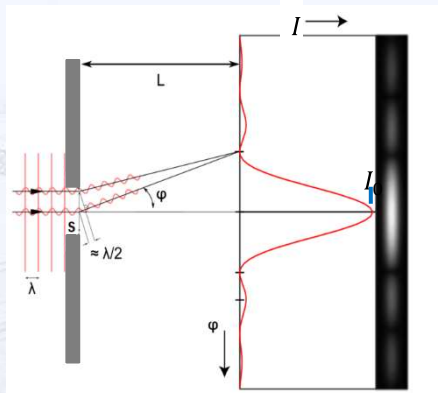
- ◆ Wavefront phase difference: $\varphi = 2\Delta h \times \sin\theta / \lambda$
- ◆ Marechal (wavefront): $\Delta h \leq \frac{\lambda}{14 \cdot \sqrt{N} \cdot 2\theta}$ (rms)
- ◆ Rayleigh : $\Delta h \leq \frac{\lambda}{4N\theta}$ (P-V)
- ◆ Δh is rms value, working in the full spatial frequency range
- ◆ $\theta \propto \lambda$, so Δh does not change much with λ
- ◆ N is the quantity of OEs

For example: $\theta=2^\circ$, $N=5$;
 $\Delta h_{\text{rms}} = 0.55 \text{ nm}$, $\Delta h_{\text{p-v}} = 1.7 \text{ nm}$

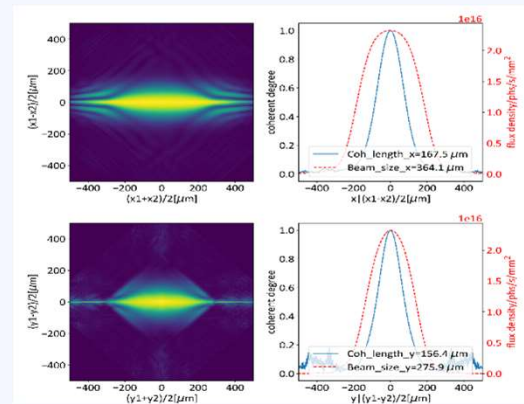
For HALF, $\Delta h_{\text{rms}} \sim 0.5 \text{ nm}$,
 $\Delta h_{\text{p-v}} \sim 2 \text{ nm}$



Influence of height error on coherent light



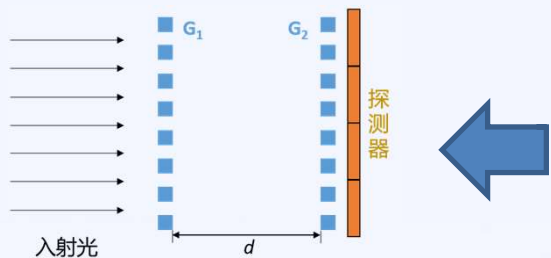
Control diffraction effect



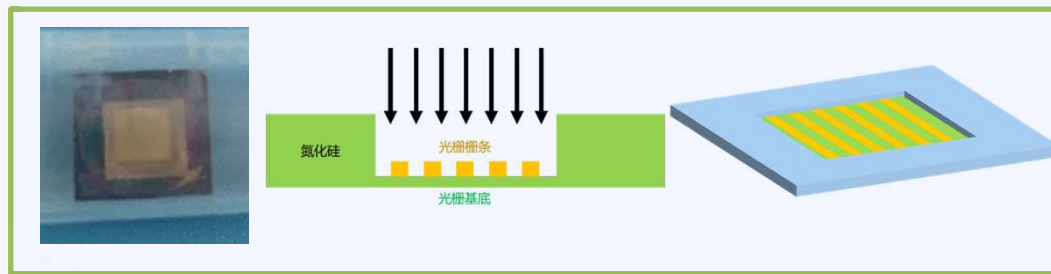
Coherence simulation⁹

Coherence and wavefront measurement

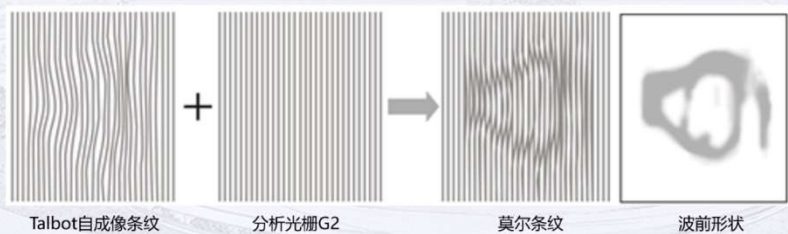
HALF requires high-precision measurement of beam quality.



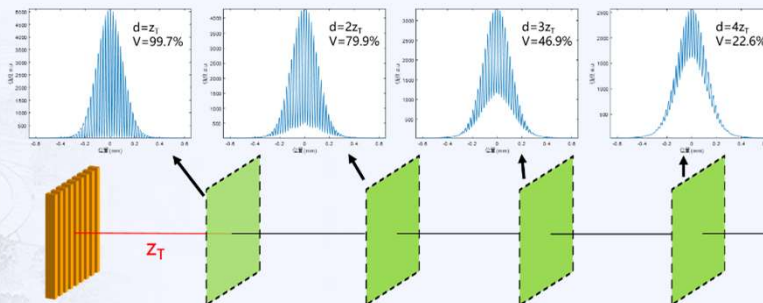
Talbot interferometer



Thin substrate / high aspect ratio transmissive optics

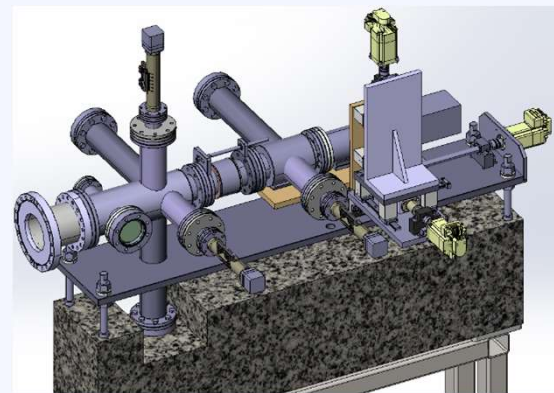
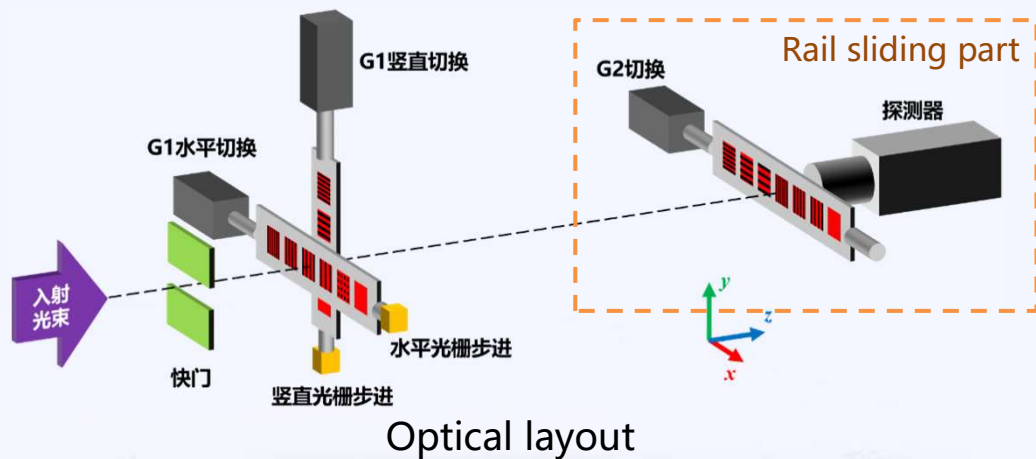


Wavefront retrieval based on Moiré fringes



Spatial coherence measurement based on visibilities at variable distances

Coherence and wavefront measurement device



Chamber 3D design

A **portable, integrated device** for **spatial coherence** and **wavefront** measurement

Spatial coherence measurement tools

- Talbot interferometer
- Double slits

Wavefront measurement tools

- Talbot interferometer
- Shack-Hartmann sensor

Spectrum detector can also be installed.

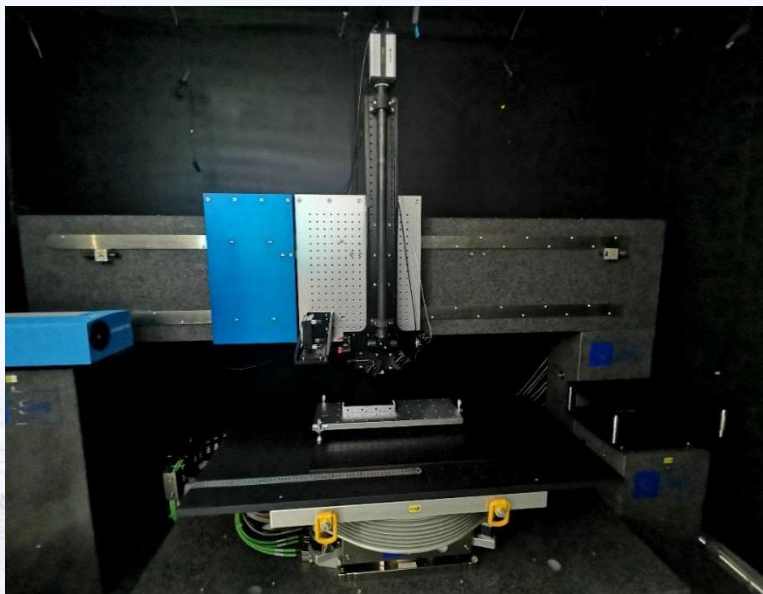
Specifications

Energy range	250-2000 eV
Local wavefront precision	100 nrad
Spatial resolution	10-25 μm (Talbot) 60-80 μm (Hartmann)
Field of view	35 \times 35 mm

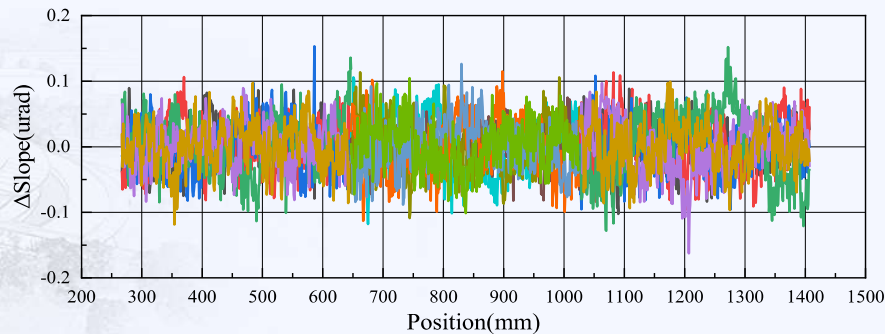
Optics: Metrology

Slope error measurement -LTP

Completed LTP system

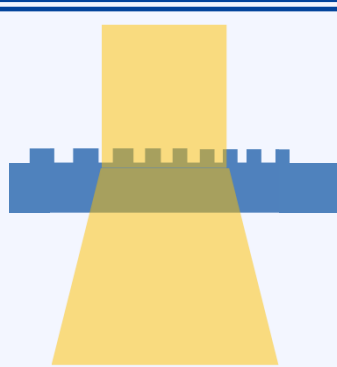
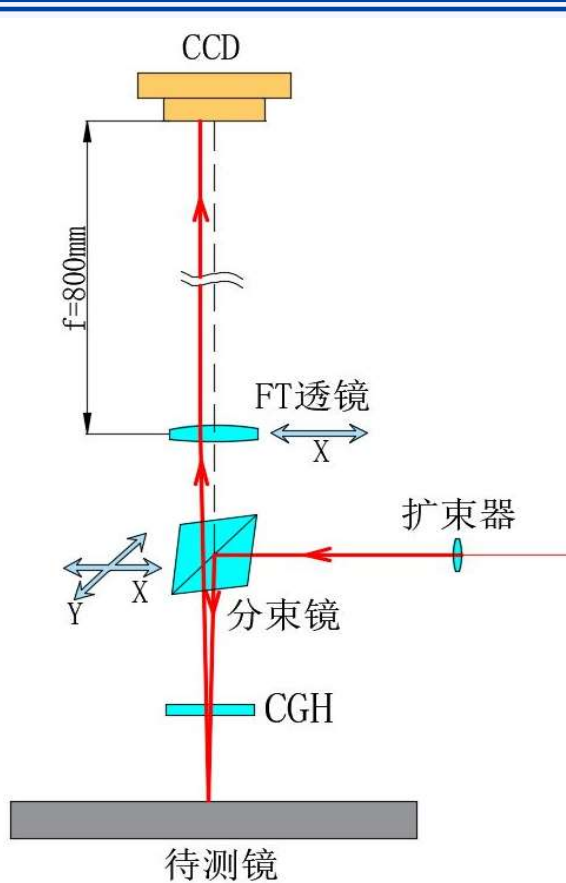


Item	Acceptance index	Measured data
Test accuracy for flat surfaces (nrad)	100 (RMS)	50 (RMS)
Test accuracy for curved surfaces (nrad)	250 (RMS)	100 (RMS)
Angular range(mrad)	± 1.5	± 1.5
Length range (mm)	1000	1000



Repeatability for flat mirrors : 37.5nrad

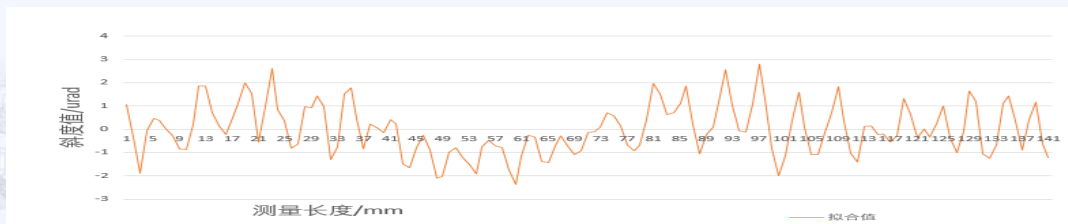
Test Scheme for the Profile of Small-Curvature Mirrors



Cylindrical CGH



Cylindrical compensating mirror



Measured sagittal shape of a Cylindrical mirror ($\rho=89.3\text{mm}$)
repeatability : 25nrad (rms)

Optical Testing Instruments



ZYGO Verifire HDF

Performance:

Optical Lateral Resolution: $50\mu\text{m}$

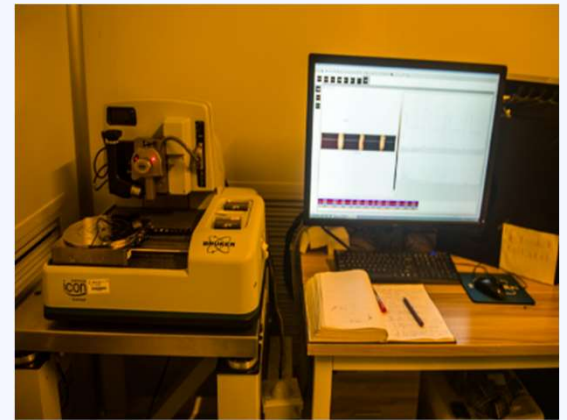
(Includes $3.4\text{k} \times 3.4\text{k}$ @ 96 Hz camera) .

UltraFlat reference flat mirror: $6''$ 4%

Reflectivity, $\lambda/40\mu\text{m}$

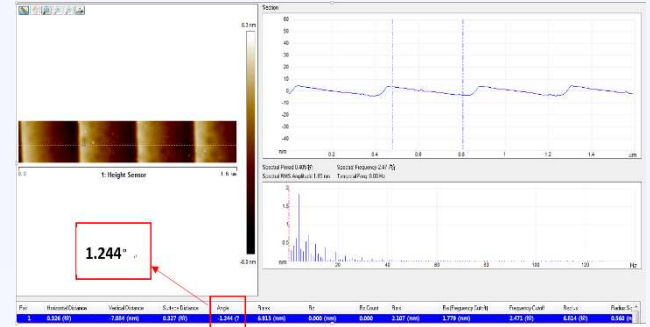
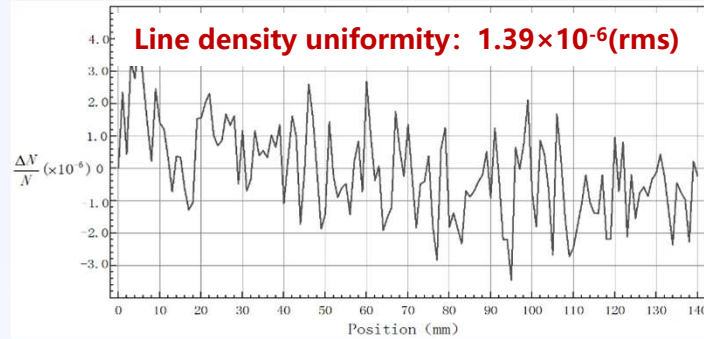


**White Light Interferometric
Microscope**



AFM

Optics: Diffraction grating R&D

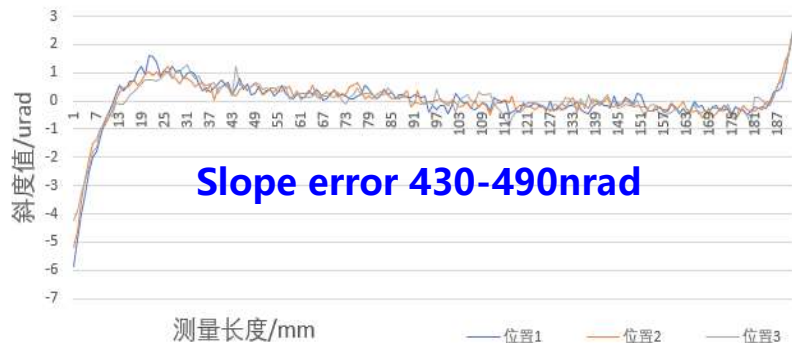


- ◆ Laminar and blazed, minimum blazed angle 0.8° , Verified to achieve 200nrad
- ◆ Production process: Holographic exposure, ion beam etching, wet etching
- ◆ More than 60% gratings are expected to be self developed

A small step forward in ion beam polishing

Dimensions of substrate: $200 \times 40 \times 50 \text{mm}^3$, (Mainly used for grating substrates)

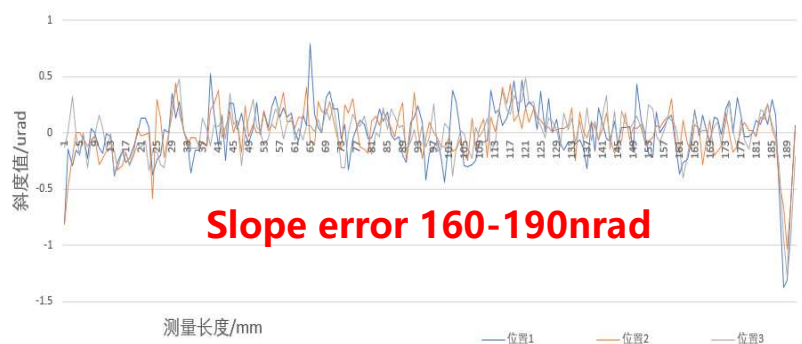
平面反射镜3个不同位置扣除各自拟合斜度值后的斜度值



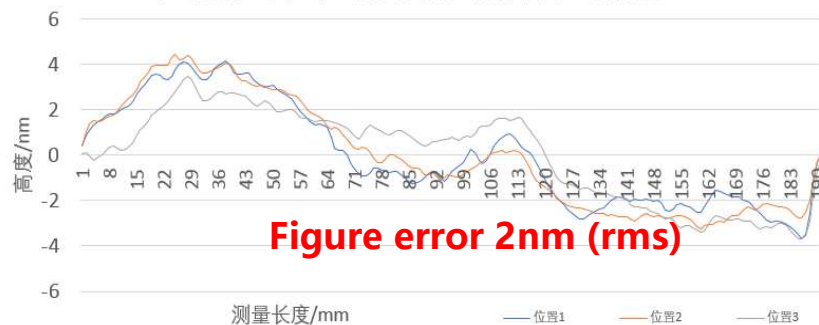
平面反射镜3个不同位置的扣除各自拟合半径值后的高度值



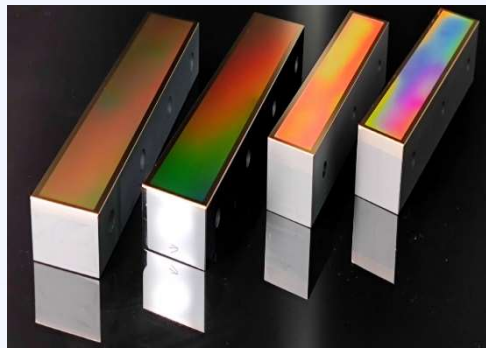
平面反射镜3个不同位置扣除各自拟合斜度值后的斜度值



平面反射镜3个不同位置的扣除各自拟合半径值后的高度值



Gratings used for HLS beamlines



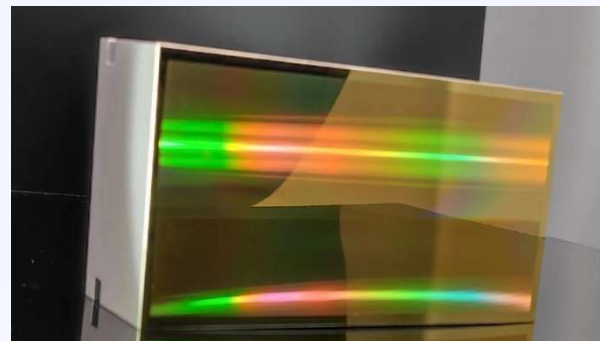
Metrology beamline

300 g/mm, 600 g/mm
VLS: 300 g/mm, 1400 g/mm



ARPES beamline

2400 g/mm, blazed
spherical, $R = 9298\text{mm}$
 $140 \times 30 \times 30\text{mm}^3$

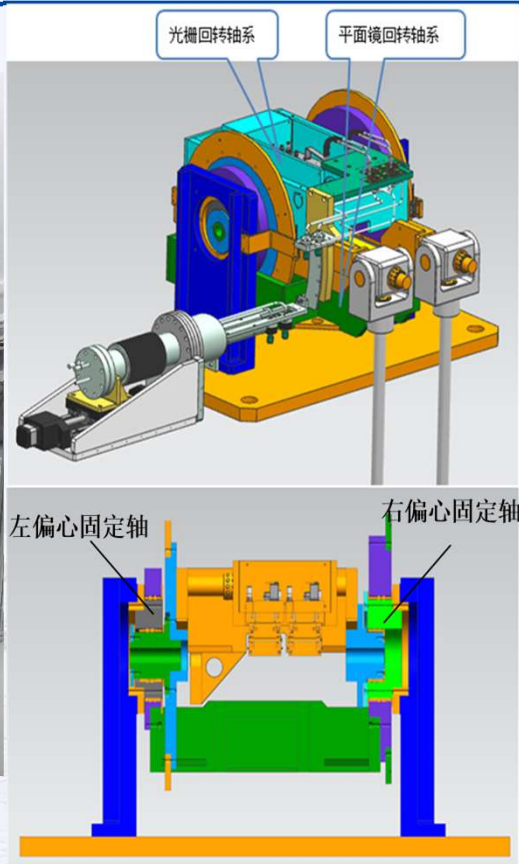


Mass Spectrometry beamline

400 g/mm, blazed, $180 \times 80 \times 50\text{mm}^3$

- ◆ 9 gratings had been used for beamlines of HLS.
- ◆ 4 gratings of them are blazed

Mechanism: PGM

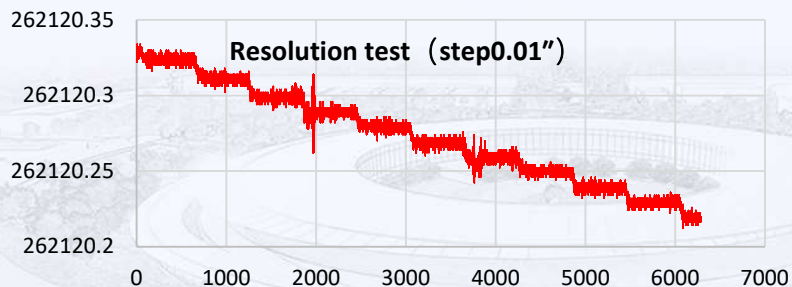


- ◆ Self developed Close-packed ball bearings were used to replace commercial angular contact bearings.
- ◆ Provide better accuracy and support stability

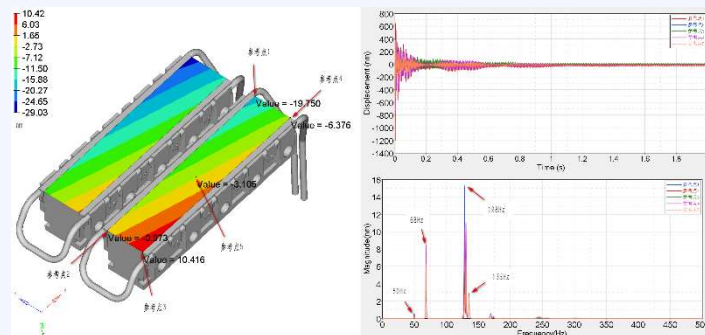
Performance of PGM

Pitch rotation range	-3°~16°
Resolution	0.01"
Pitch repeatability	0.03"
Pitch stability by encoder	0.01"@ 2 hours
Pitch stability by autocollimator	0.04"@ 2 hours*

* Testing ground is not good



Mechanical performance meets the requirement of 100,000 energy resolving power

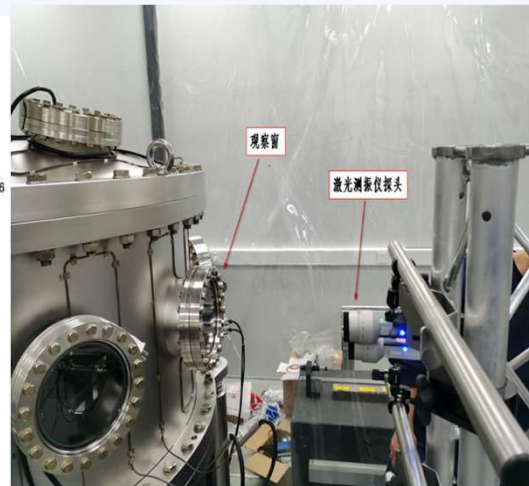
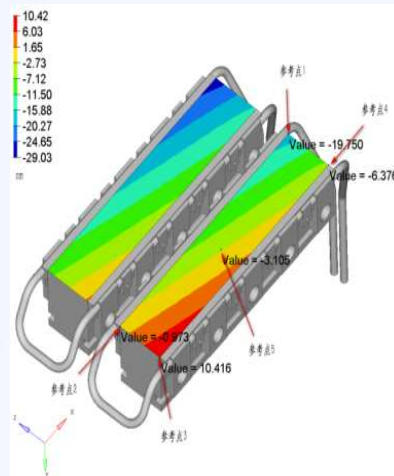
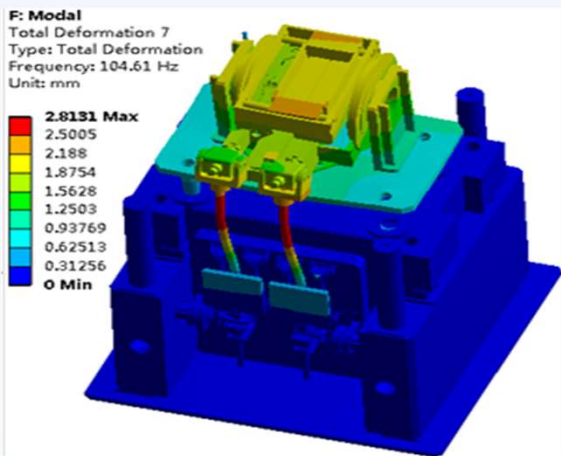


Simulation of Flow Induced Vibration of Grating

Cooling Current	0	0.5L/min	1L/min	1.5L/min	2L/min
Grating-Open Loop	16.2nrad	19.2nrad	20.2nrad	23.0nrad	29.7nrad
Grating-Close Loop	14.6nrad	14.3nrad	16.7nrad	19.8nrad	26.0nrad
PM-Open Loop	13.0nrad	15.4nrad	14.3nrad	12.5nrad	18.4nrad
PM-Close Loop	7.6nrad	3.5nrad	6.2nrad	5.2nrad	7.5nrad

Flow Induced Vibration tested by encoder

Stability simulation and measuring equipments



Thermal load overview

Beamline	Energy (eV) (maximum thermal load)	Thermal load (W)	Thermal density W/mm ²	Thermal load (W)	Thermal density W/mm ²	Thermal load (W)	Thermal density W/mm ²
		First mirror		PM in PGM		Grating	
BL01	25	< 0.1	< 0.001	< 0.1	< 0.001	0.25	1.5E-4
BL02	6	413.6	0.107	10.8	0.041	0.19	2.2E-4
BL03	45	224.4	0.224	19.6	0.119	0.55	24.5E-4
BL04	250	179.7	0.068	125.6*	0.128*	6.50*	32.4E-4*
BL05	180	213.0	0.165	65.7	0.140	3.54	30.3E-4
BL06	250	77.9	0.069	45.6	0.092	2.54	36.6E-4
BL07	250	64.5	0.030	100.9	0.209	--	--
BL08	770	20.0	0.011	60.1	0.165	1.95	27.9E-4
BL10	240	64.8	0.045	59.0	0.286	0.22	3.1E-4
		First mirror		Crystal #1			
BL08	2300	15.3	0.014	39.1	2.81	--	--
BL09	2100	45.9	0.049	91.6	9.94	--	--

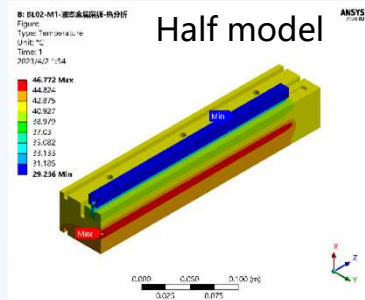
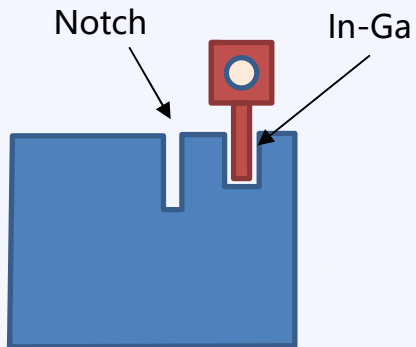
Water cooling

LN cooling

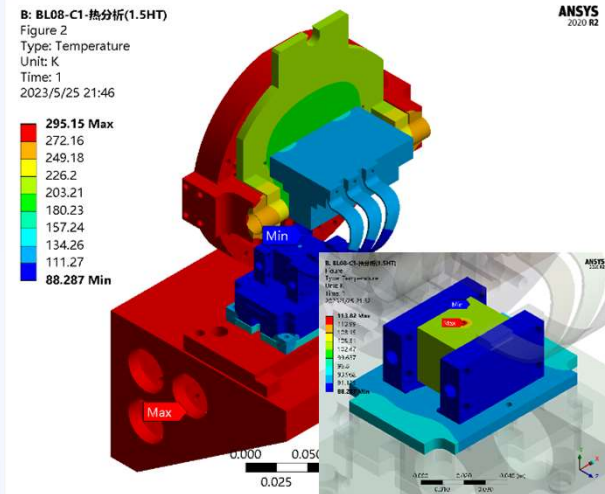
Slope error is about 100nrad~500nrad

Water Cooling and LN Cooling

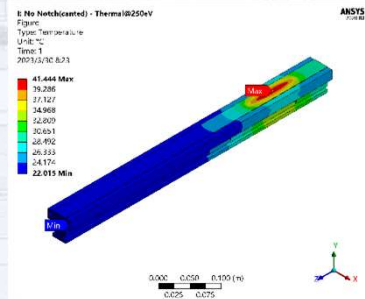
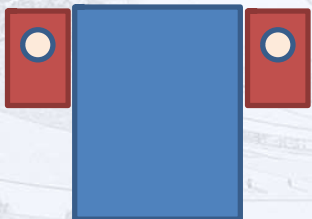
Single Side Water Cooling via In-Ga Bath



Liquid Nitrogen Side Cooling



Top-Side Water Cooling (TIM: In or In-Ga)



Welcome to HALF

The Door of HALF is open for you

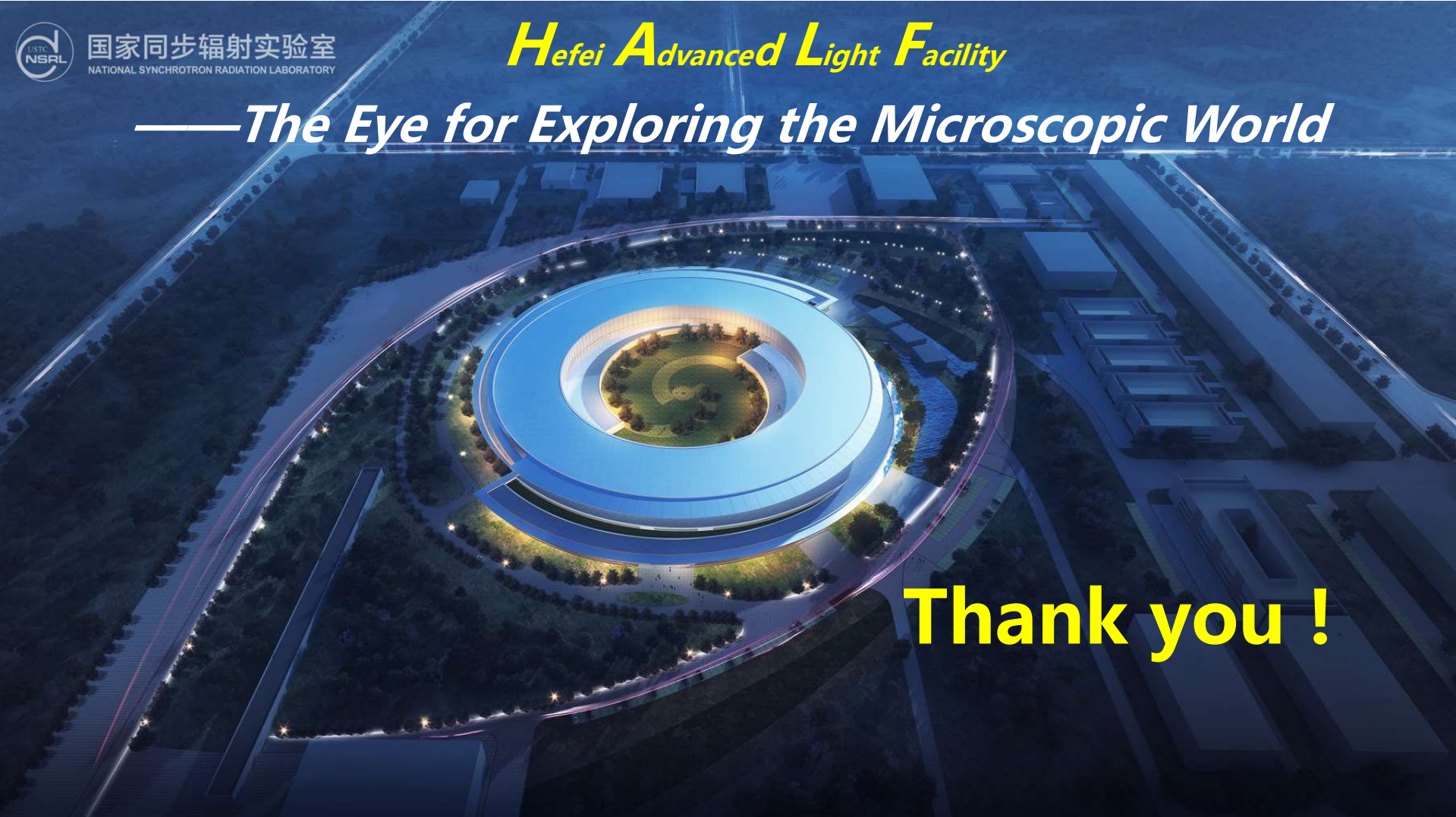
- Looking for **experienced beamline engineers**

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